TOSHIBA 2SC2641

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 2 6 4 1

UHF BAND POWER AMPLIFIER APPLICATIONS

Output Power: Po=6W (Min.) $(f=470MHz, V_{CC}=12.6V, Pi=1W)$

MAXIMUM RATINGS ($Tc = 25^{\circ}C$)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	35	V
Collector-Emitter Voltage	v_{CEO}	17	V
Emitter-Base Voltage	V_{EBO}	3.5	V
Collector Current	$I_{\mathbf{C}}$	1.4	A
Collector Power Dissipation	PC	15	W
Junction Temperature	Tj	175	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-65~175	°C

Unit in mm 2-R1.6 2-R3/ 16 18±0.3 7 MAX **EMITTER** 1. BASE 2. **EMITTER** COLLECTOR **JEDEC** EIAJ TOSHIBA 2-7A1A

Weight: 1.9g

ELECTRICAL CHARACTERISTICS (Tc = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 15V, I_{E} = 0$	_	_	1	mA
Collector-Base Breakdown Voltage	V _(BR) CBO	$I_C=2mA$, $I_E=0$	35	_		V
Collector-Emitter Breakdown Voltage	V _(BR) CEO	$I_{C} = 10 \text{mA}, I_{B} = 0$	17		1	V
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	$I_{E} = 0.2 \text{mA}, I_{C} = 0$	3.5	_	_	V
DC Current Gain	$h_{ extbf{FE}}$	$V_{CE}=5V, I_{C}=1A *$	10		l	
Collector Output Capacitance	$C_{\mathbf{ob}}$	$V_{CB} = 10V, I_E = 0$ f=1MHz	_	_	25	pF
Output Power	Po	(Fig.) V _{CC} =12.6V, f=470MHz Pi=1W	6	_	_	W
Power Gain	G_p		7.7	_		dB
Collector Efficiency	$\eta_{\mathbf{C}}$		60	_	-	%
Series Equivalent Input Impedance	Zin	V _{CC} =12.6V, f=470MHz Po=6W	_	1.6 +j4.5		Ω
Series Equivalent Output Impedance	Z _{out}		_	6.5 +j5	_	Ω

^{*} Pulse Test : Pulse Width ≤ 100 µs, Duty Cycle ≤ 3%

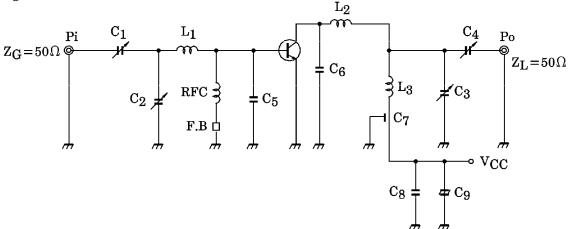
CAUTION

Beryllia Ceramics is used in this product. The dust or vapor can be dangerous to humans. Do not break, cut, crush or dissolve chemically. Dispose of this product properly according to law. Do not intermingle with normal industrial or domestic waste.

TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.

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Fig. Po TEST CIRCUIT



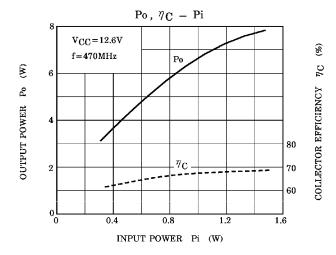
 $C_1, C_2, C_3, C_4 : \sim 20 pF$

 $\begin{array}{ccc} {\rm C}_5, {\rm C}_6 & : & 10 {\rm pF} \\ {\rm C}_7 & : & 0.01 \mu {\rm F} \\ {\rm C}_8 & : & 0.02 \mu {\rm F} \\ {\rm C}_9 & : & 10 \mu {\rm F} \end{array}$

 $L_1, L_2 : 5 \times 20 \times 0.1 mm$ COPPER PLATE

L₃ : ϕ 1 SILVER PLATED COPPER WIRE, 10ID, 2T RFC : ϕ 0.5 ENAMEL COATED COPPER WIRE, 7ID, 10T

F.B : FERRITE BEAD



CAUTION

These are only typical curves and devices are not necessarily guaranteed at these curves.

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